

Supporting Information

FeVO₄-based solution- processed all oxide self-biased fast photodetectors.

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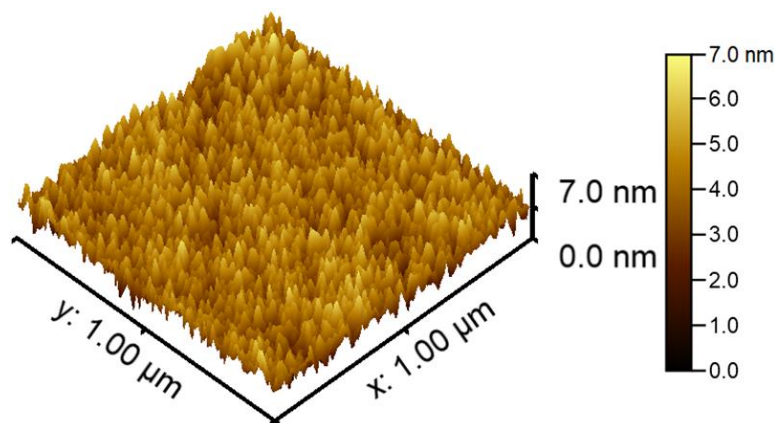


FIG. S1. Three-dimensional AFM image of FeVO₄ (FVO) thin film on a quartz substrate.

Table S1. Atomic percentages of the constituent elements in the solution-processed FVO thin films.

Element name	Atomic (%)
Fe	16.04
V	15.09
O	62.56
C	6.31

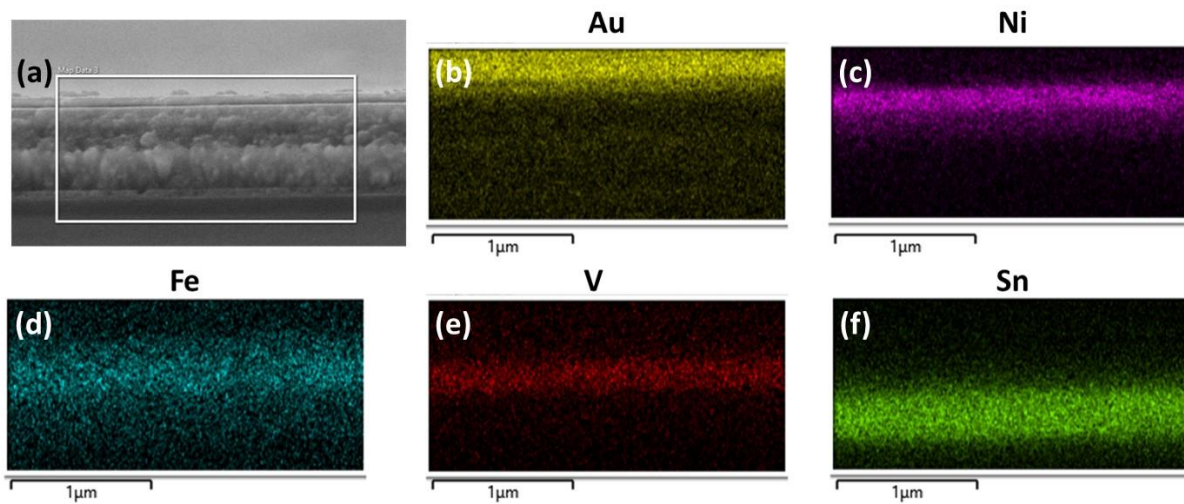


FIG. S2. (a) Cross-section FESEM image of FVO-based photodetector. Corresponding EDS elemental mapping graphs of (b) Au, (c) Ni, (d) Fe, (e) V and (f) Sn are present in the bottom FTO substrate.

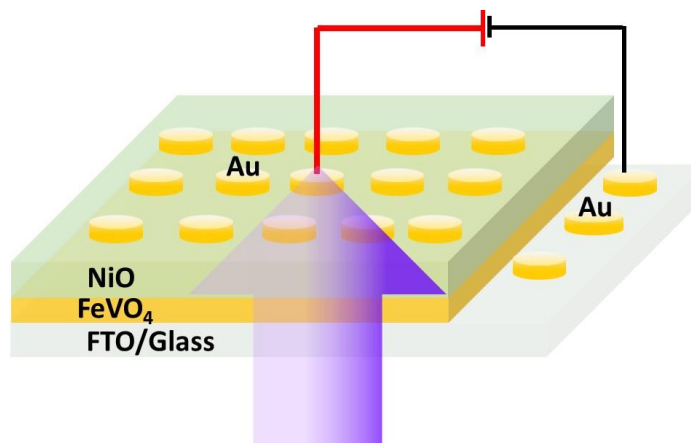


FIG. S3. The schematic of the electrical measurement for n-FVO/p-NiO photodetector.

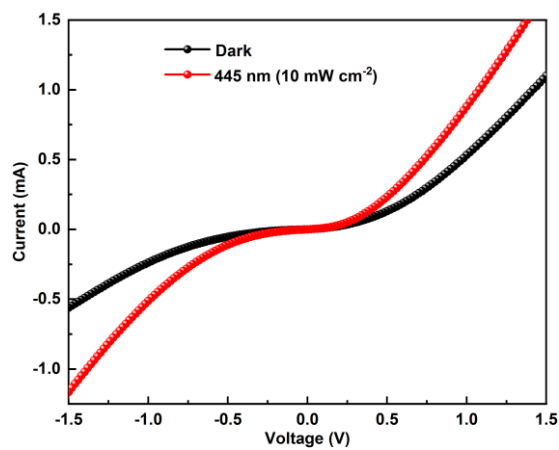


FIG. S4. *I-V* characteristics of the n-FVO/p-NiO heterojunction device under dark and visible light (445 nm, 10 mW cm⁻²).

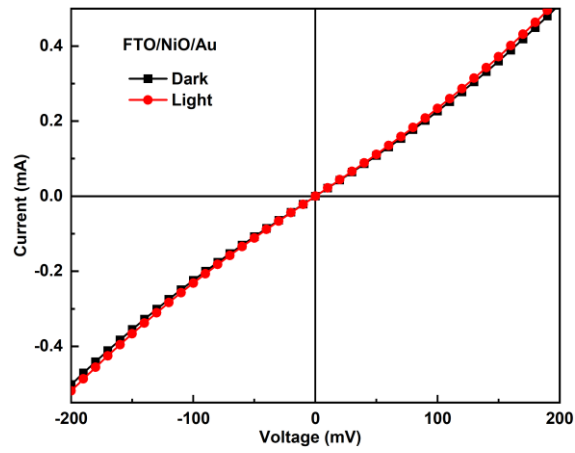


Fig. S5. I - V characteristics of FTO/NiO/Au device under dark and 445 nm light illumination.

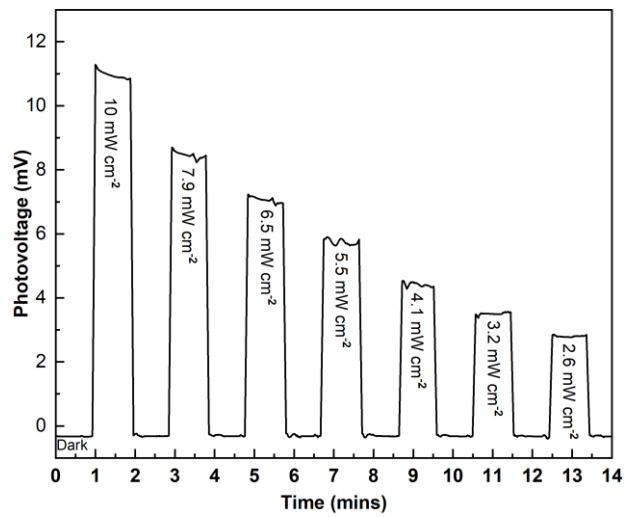


Fig. S6. The photovoltage-time curve with the change of incident light intensity.

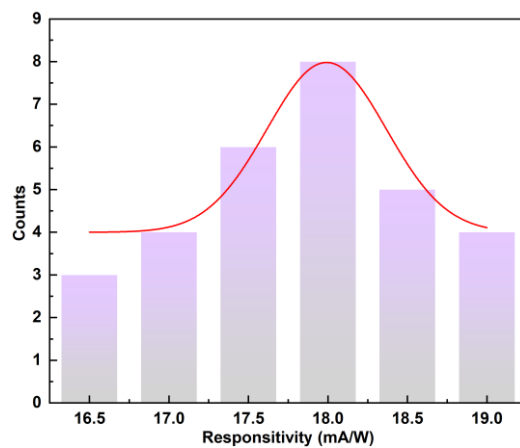


Fig. S7. Histogram showing the average responsivity (R) extracted from the J - V curves of 30 FVO-based photodetectors.

Table S2. Comparison diagram of representative solution-processed self-biased all-oxide photodetectors.

Device	Wavelength (nm)	Intensity (mW cm ⁻²)	Photoresponsivity (mA W ⁻¹)	Detectivity (Jones)	Rise time (ms)	Fall time (ms)	Ref.
BiFeO ₃ /XTiO ₃ (X-Sr, Zn, Pb)	500	8	1.3	3×10 ¹⁰	19	23	¹
CuBi ₂ O ₄ /PZT	425	0.00751	0.24	2.40×10 ¹⁰	24	46	²
ZnO NRs/Cu ₂ O	425	25	8.2	-	140	360	³
Co ₃ O ₄ -ZnO	520		8.3	3.14×10 ¹²	20	90	⁴
FVO/NiO (This work)	445	6.5	18	5.3×10 ¹⁰	46	47	
Au/BiVO ₄ /Pt	520	150	0.3	5×10 ⁹	16.5	5.8	⁵
Pt/LNO/Bi _{1.5} FeO ₃ /Au	500	0.2	1.515	1.35×10 ¹¹	6	15	⁶

References

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